

Search Notes

Application/Control No.

10/817,177

Examiner

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Applicant(s)/Patent under
Reexamination

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Art Unit

2681

SEARCHED

Class	Subclass	Date	Examiner
455	415	10/4/2005	HN
	410		
	411		
	418		
	422.1		
Updated	search	5/24/2006	HN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
455	415	5/24/2006	HN
	410		
	411		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT). See search history printout.	10/4/2005	HN
Interference search printout.	5/24/2006	HN